

About V. I. Vernadsky IGIC NASU

The V.I. Vernadsky Institute of General and Inorganic Chemistry was founded in 1918 by Academician V.I. Vernadsky. It was originally a Chemical Laboratory in Kyiv and later joined with the research department of chemistry at the Kyiv Polytechnic Institute. In 1929, it became the Research Institute of Chemistry and in 1931, it joined the Ukrainian SSR Academy of Sciences as the Institute of Chemistry. It was renamed the Institute of General and Inorganic Chemistry in 1945 and received its current name in 1993.



The Institute has founded five chemical institutions and is now a state nonprofit institution and the main scientific center for fundamental and applied research in various fields of chemistry. It actively cooperates with domestic and foreign universities, academic institutions, research centers, and industrial associations.

Today, the main practical purpose of the scientific activity of V.I. Vernadsky IGIC of the NAS of Ukraine is the creation of highly efficient, environmentally friendly, energy- and resource-saving technologies, including the inclusion of the secondary raw material in the production process, which will contribute to reducing the man-caused environmental impact.

Aim of V. I. Vernadsky IGIC NASU in the project:

the synthesis of new microwave materials with permittivity from 10 to 150 and varied dielectric quality factor Q which are needed to create resonator rectenna for energy harvesting and electromagnetic sensing, study their dielectric properties, and develops ways to control the dielectric properties in order to best match the design requirements for the created metamaterials.

Deliverables of V. I. Vernadsky IGIC NASU in the project:

- microwave dielectrics with $Q_{10\text{GHz}} \sim 5000\text{-}7000$ based on multiphase systems with the volumetric thermal compensation effect.
- microwave dielectrics based on a mixture of perovskite and spinel phases with $Q_{10\text{GHz}} \sim 10000$
- Optimization of parameters of microwave dielectric resonators prototypes.

V. I. Vernadsky IGIC NASU team



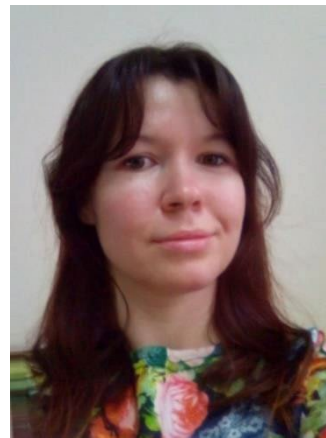
Anatolii Belous
Academician of NAS of
Ukraine, Professor Doctor
of Chemical Sciences,
PPCD

Coordinating team
members' research,
analyzing results, and
discussing them with
partners



Oleg V'yunov,
Senior scientist,
Ph.D,
senior researcher

Investigation of
crystal structure,
phase formation and
ceramic properties



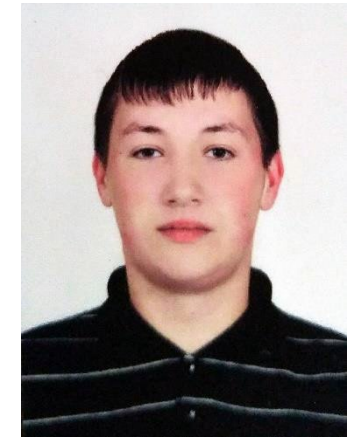
**Tetiana
Plutenko,**
Ph.D,
researcher

Synthesis and
sintering of
ceramic samples



**Oleksandr
Fedorchuk,**
Ph.D,
researcher

Stipendiary,
characterization of
dielectric parameters
of ceramic samples



**Pavlo
Torchyniuk,**
Ph.D,
researcher

Stipendiary,
synthesis and
sintering of
ceramic samples

**V. I. Vernadsky IGIC NASU, additional specialists
involved in the execution of the project**



Solopan Serhii,
Senior researcher,
Dr.Sc.,
senior researcher



Kovalenko Leonid,
Ph.D,
senior researcher

Some equipment for synthesis of MW dielectric materials



Analytical scales for weighing the initial reagents and equipment for synthesis

Drums and layers for planetary mill PM-100



Equipment for deposition of thin films and electrodes
(a) VUP-5; (b) SC7620 and CA7625



Tube furnace for rapid heating
GSL-1500X-RTP50



High-temperature furnace
KSL-1500X



Some equipment for mechanical preparation of MW dielectric materials



Sanding and polishing machine with automatic pneumatic head Forcimat & Forcimol 1V



Equipment for diamond cutting

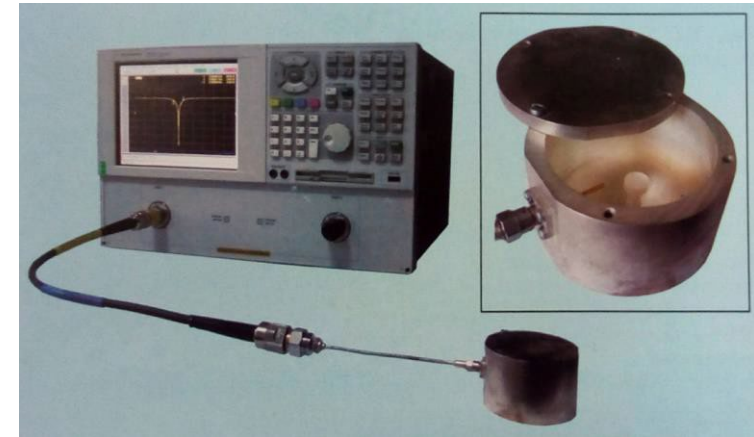
Some equipment for investigation of MW dielectric materials



Electron microscope
SNE-4500M

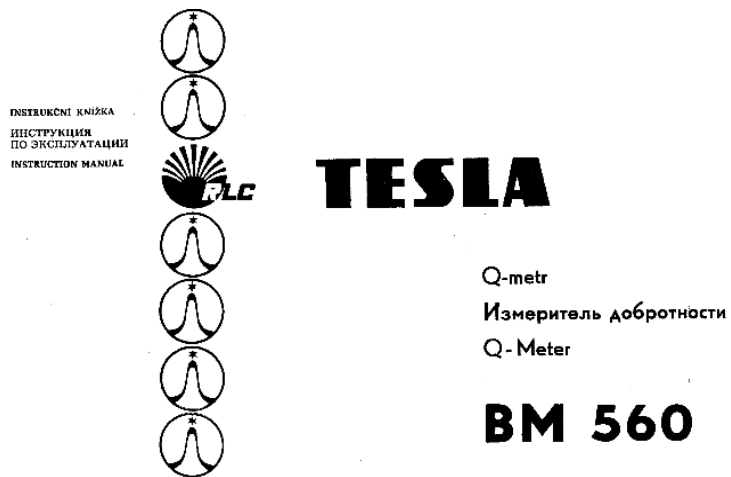


Experimental setup for
impedance analysis



Setup for analysis of MW
dielectrics Agilent N5230A

Measurement of dielectric parameters in the radio frequency range



Experimental dielectric samples with permittivity of ~ 17 (1) and ~ 33 (2) for measurement in the radio frequency range.



Samp le type	Dia- meter, mm	Thick- ness, mm	Permit- tivity (ϵ)	Dielectric losses (tan δ)
1	16.201(4)	1.520(4)	17.7(8)	0.0010(3)
2	16.996(4)	1.480(4)	33.6(2)	0.0010(3)

Measurement of dielectric parameters in the microwave range

Agilent 2-Port PNA-L Microwave Network Analyzer

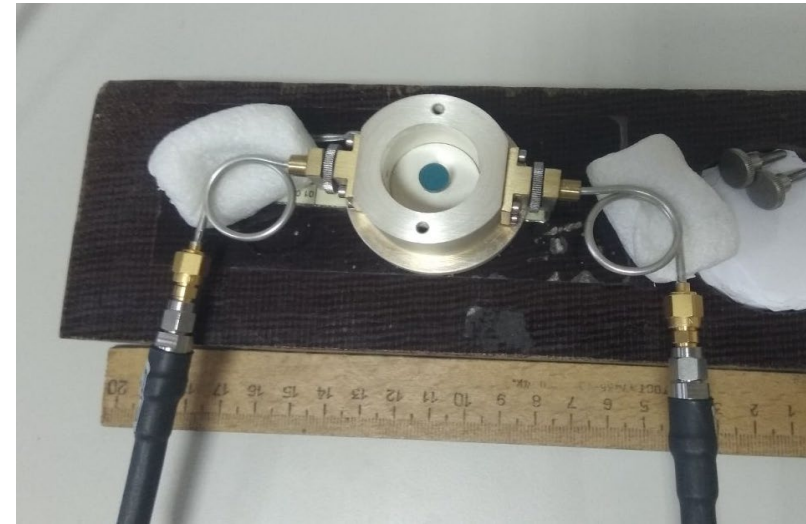
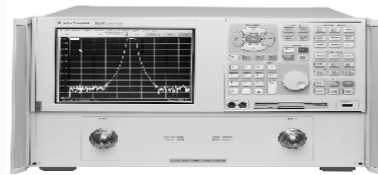
Please note: This document *does not* contain Agilent's most up-to-date PNA-L network analyzer portfolio. This document is available for reference only for customers using Agilent's legacy network analyzers. To view the current Agilent 2-port PNA-L Microwave Network Analyzer Data Sheet [click here](#).

N5230A
300 kHz to 6, 13.5 GHz
10 MHz to 20, 40, 50 GHz

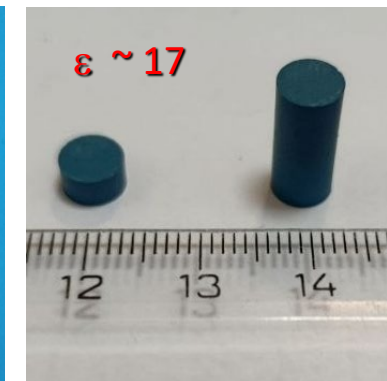
Data Sheet



Agilent Technologies

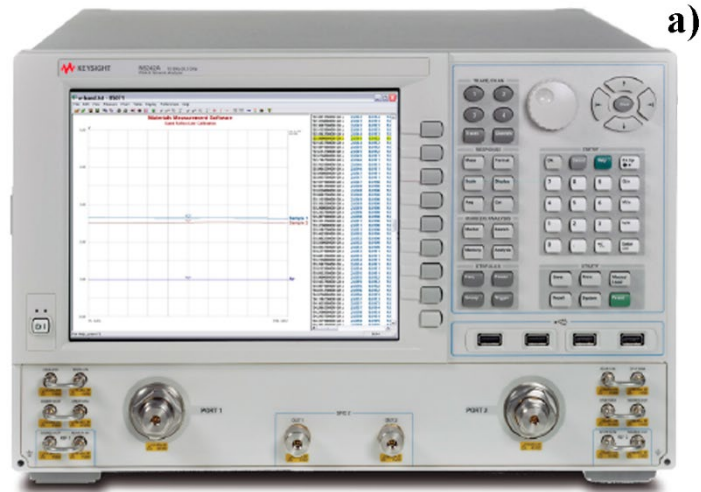


QWED, Warsaw, Poland

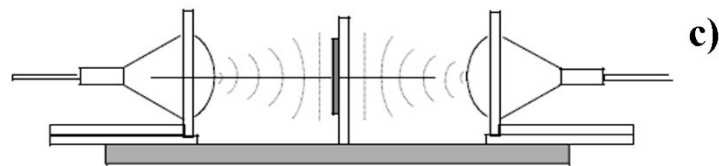
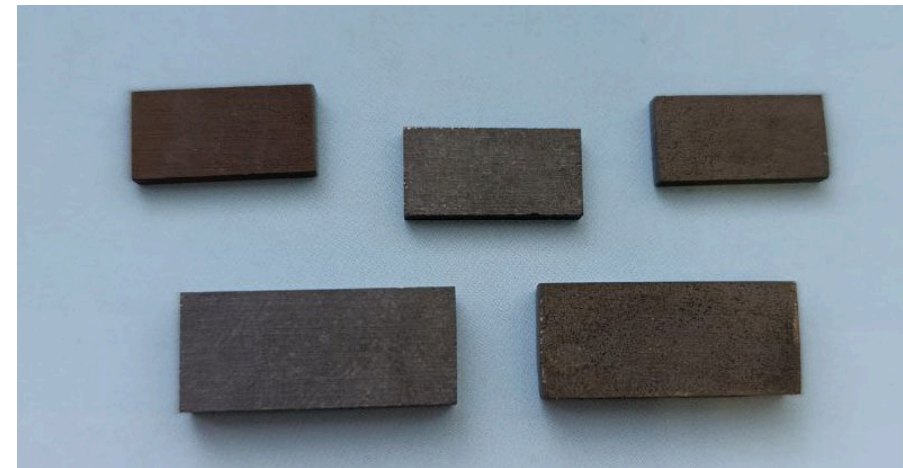
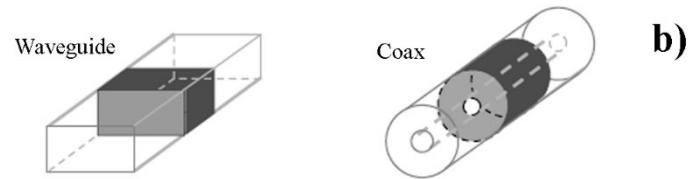


Samples characterized in the radio
frequency and microwave ranges

Measurement of radio-absorbing materials



For investigating of MW characteristics of radio-absorbing materials, three approaches can be used: measurements in a waveguide, in a coaxial line, and in free space.



Microwave vector network analyzer (a), measurement in a rectangular metal waveguide and coaxial transmission line (b), and in free space (c).

Samples used to investigate the microwave characteristics of radio-absorbing materials in a waveguide. They must be prepared with geometric dimensions and shapes that exactly correspond to the internal parameters of the waveguide, as any gaps or irregularities reduce measurement accuracy.